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Call for Papers

IEEE Transactions on Device and Materials Reliability

In an era of rapidly increasing density and integration of devices, *IEEE Transactions on Device and Materials Reliability* (T-DMR) is dedicated to providing leading information that is critically relevant to the creation of reliable products. This fully peer-reviewed archival publication is available online and via quarterly library subscription.

The broad scope of T-DMR includes, but is not limited to:

- The reliability of electronic, optical and magnetic devices, MEMs devices, micro-systems and packages
- The reliability of the materials used in these devices, micro-systems and packages
- Properties of the interfaces, surfaces, and microstructure that impact the reliability of materials
- Fabrication processes that modulate materials and device reliability

Original work is solicited on the measurement, physical analysis, and fundamental understanding of the reliability of electronic devices and materials from the concept stage through research and development, and during manufacture.

Papers to be published in the *IEEE Transactions on Device and Materials Reliability* are sought in the following areas:

- Mechanisms of failure of electronic devices and materials
- Influence of fabrication processes on failure mechanisms
- Theoretical modeling and simulation of failure mechanisms
- Reliability testing and screening methodologies for materials and devices
- Reliability impact of device and circuit design, material, and process selection

The intent of the T-DMR is to facilitate rapid dissemination of new research findings. The Editorial Board strives to expedite publication to ensure rapid dissemination of new results. Manuscripts will appear online shortly after acceptance for publication. Current publication statistics for T-DMR indicate that first reviews are complete in less than 2 months while accepted manuscripts are published on-line on average in less than 4 months.

Manuscript submission details and instructions for authors can be obtained at
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